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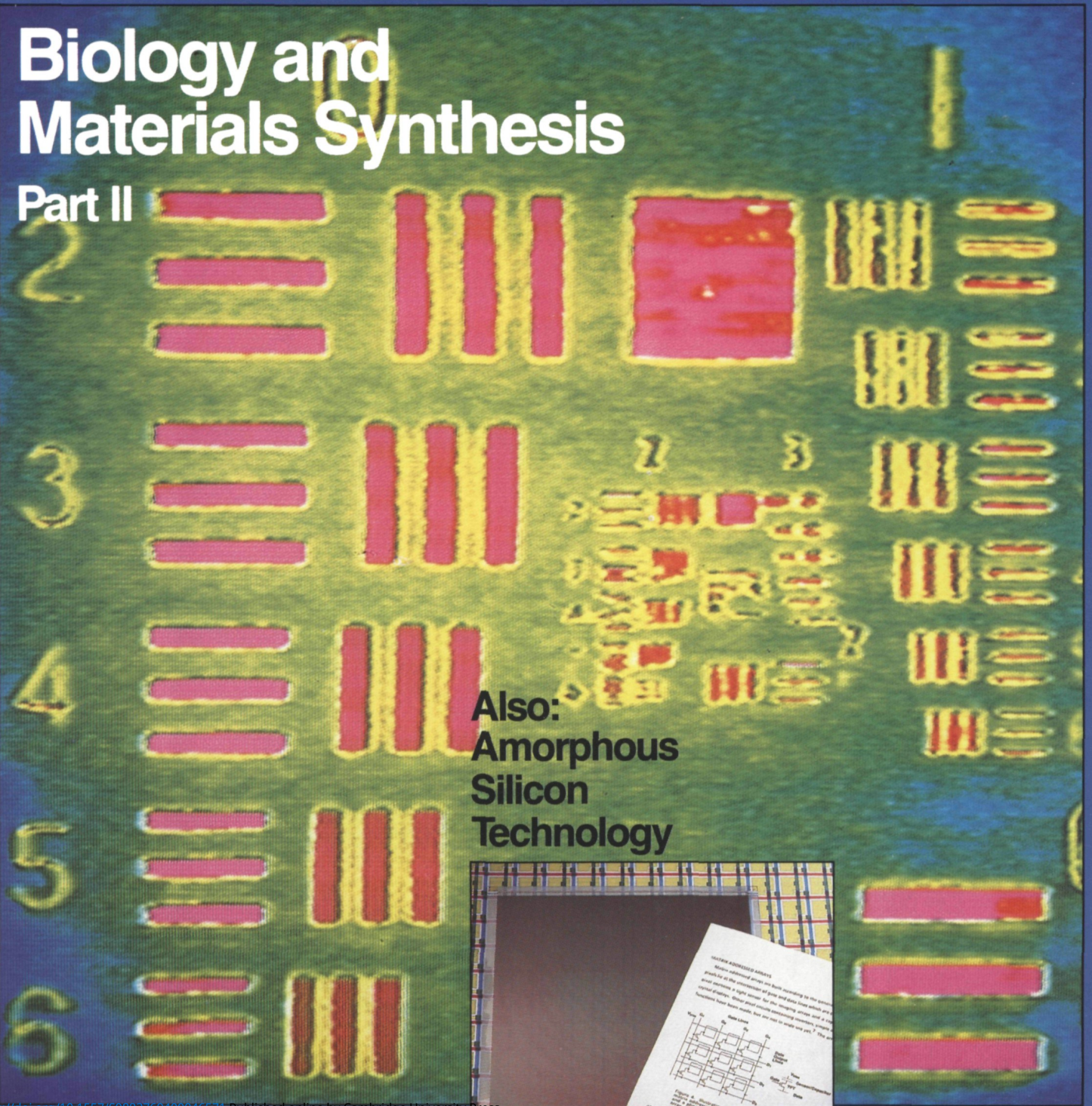
A Publication of the Materials Research Society

November 1992, Volume XVII, No. 11

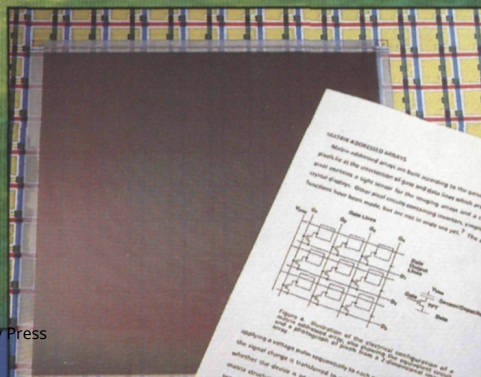


## Biology and Materials Synthesis

Part II

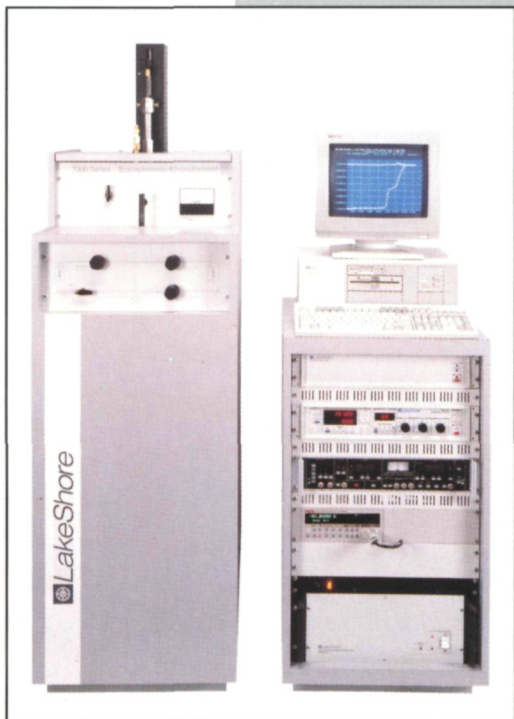


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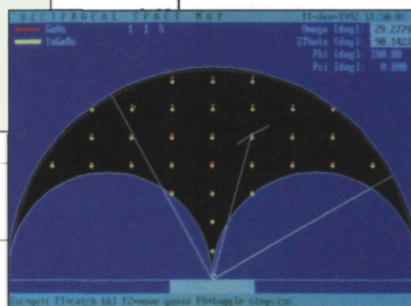
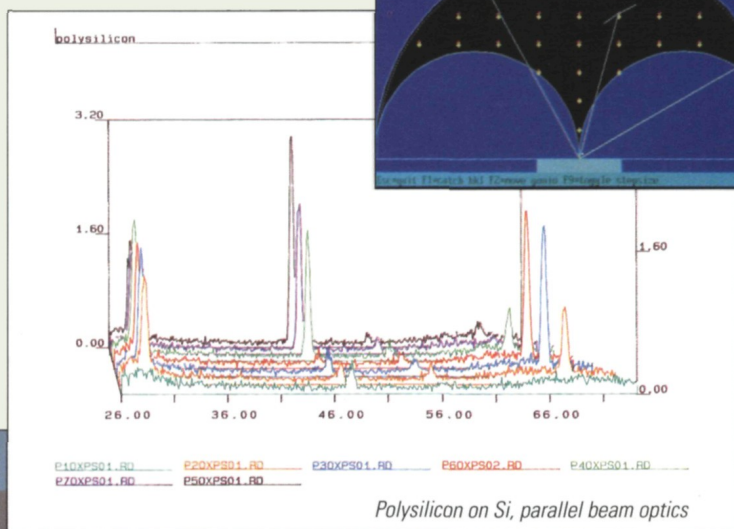
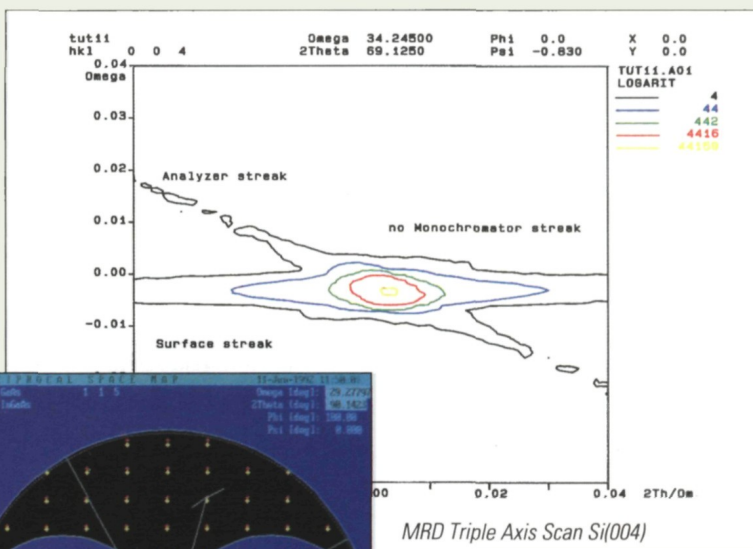
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# MRS BULLETIN

November 1992

A Publication of the Materials Research Society

Volume XVII, Number 11 ISSN: 0883-7694 CODEN: MRSBEA

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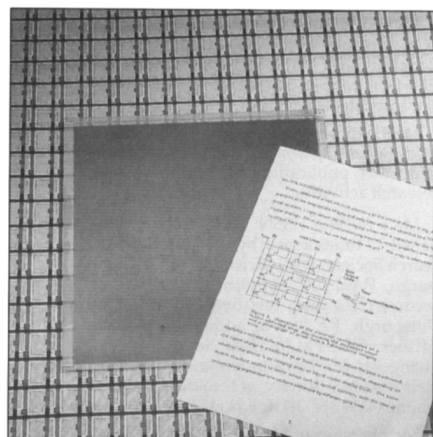
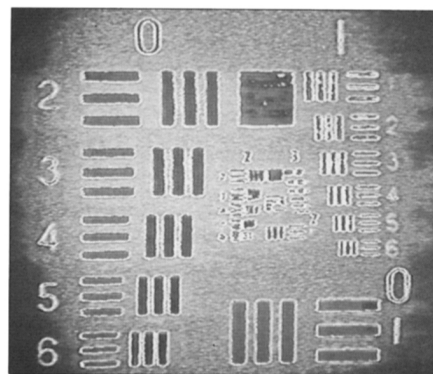
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**ON THE COVER (top):** USAF test pattern recorded as a dynamic reflection-type hologram in a bacteriorhodopsin film. The pattern is heterodyne reconstructed and the intensity distribution is visualized by false color representation. For more information on bacteriorhodopsins, see "Mutated Bacteriorhodopsins: Competitive Materials for Optical Information Processing?" by N. Hampp, C. Bräuchle and D. Oesterhelt.

**Insert (bottom):** Photograph of a large-area amorphous silicon image sensor array. See R.A. Street's article, "Amorphous Silicon Electronics," for more information on this subject.

## About the Materials Research Society

The Materials Research Society (MRS), a nonprofit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 10,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and more than 40 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is an affiliate of the American Institute of Physics.

MRS publishes symposium proceedings, *MRS Bulletin*, *Journal of Materials Research*, and other publications related to current research activities.

*MRS Bulletin* (ISSN: 0883-7694) is published 12 times a year by the Materials Research Society, 9800 McKnight Road, Pittsburgh, PA 15237. Application to mail at second class rates has been approved at Pittsburgh, PA and at additional mailing offices. POSTMASTER: Send address changes to *MRS Bulletin* in care of the Materials Research Society, at the address listed; phone (412) 367-3003; Fax (412) 367-4373

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*MRS Bulletin* is included in Current Contents/Physical, Chemical & Earth Sciences™, Research Alert, and the Materials Science Citation Index™. Back volumes of *MRS Bulletin* are available in 16mm microfilm, 35mm microfilm, or 105mm microfiche through University Microfilms Inc., 300 North Zeeb Road, Ann Arbor, Michigan 48106.

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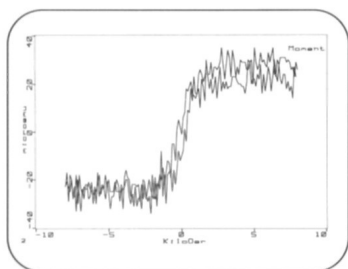
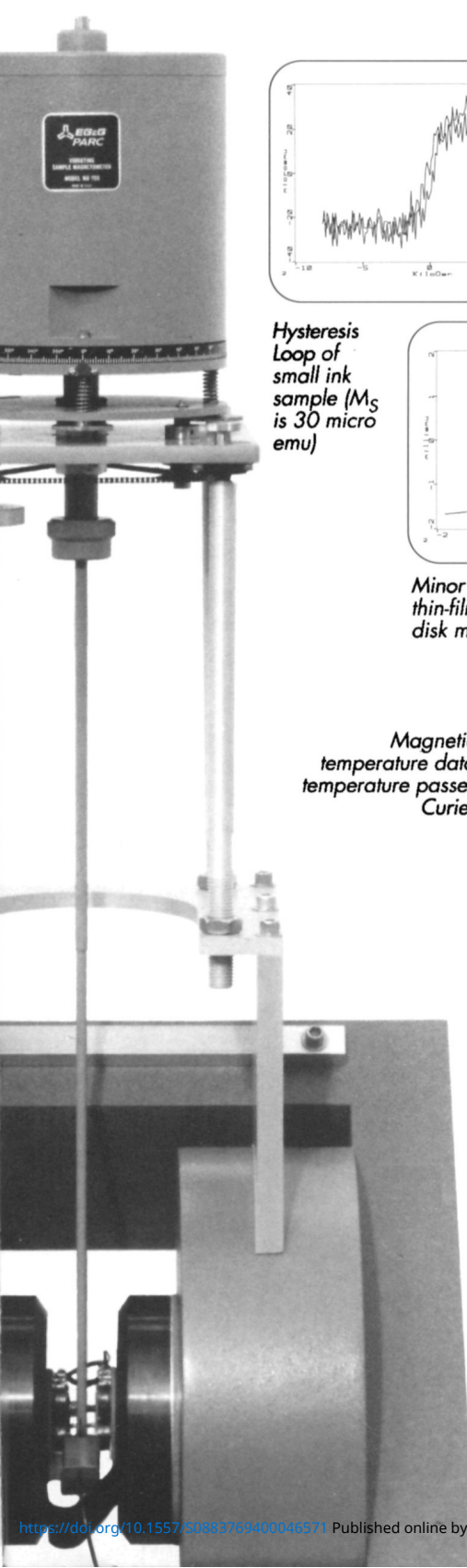
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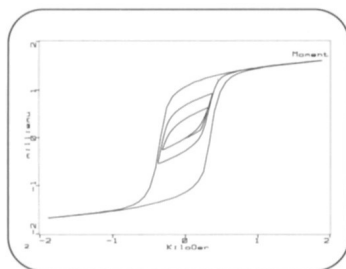
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# Nothing Beats Good Data



*Hysteresis Loop of small ink sample ( $M_s$  is 30 micro emu)*



*Minor Loops of thin-film, hard-disk material*

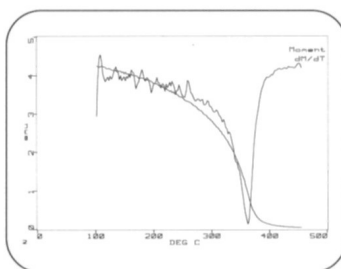
*Magnetic moment vs. temperature data of nickel as temperature passes through the Curie Temperature*

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